

N-Channel 40-V (D-S), 175 °C MOSFET

PRODUCT SUMMARY			
V _{DS} (V)	r _{DS(on)} (Ω)	I _D (A) ^a	Q _g (Typ)
40	0.0065 at V _{GS} = 10 V	20	53.6 nC
	0.008 at V _{GS} = 4.5 V	20	

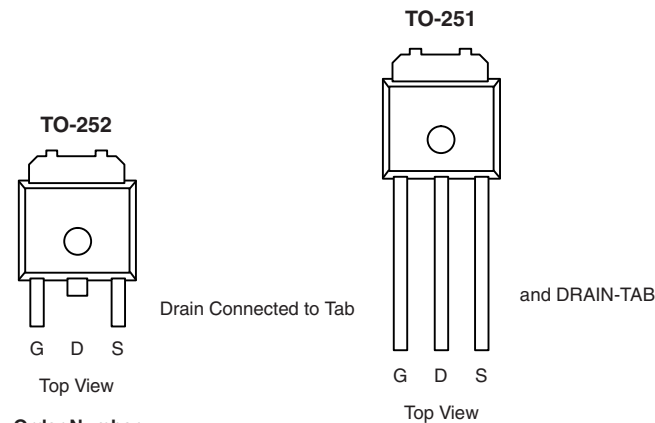
FEATURES

- TrenchFET[®] Power MOSFET
- 100 % R_g & UIS Tested


RoHS
COMPLIANT

APPLICATIONS

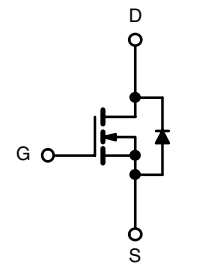
- LCD TV Inverter
- Secondary Synchronous Rectification


Order Number:

SUU50N04-06P-E3 (Lead (Pb)-free)

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SUU50N04-06P-E3 (Lead (Pb)-free)



N-Channel MOSFET

ABSOLUTE MAXIMUM RATINGS T _A = 25 °C, unless otherwise noted				
Parameter		Symbol	Limit	Unit
Drain-Source Voltage		V _{DS}	40	V
Gate-Source Voltage		V _{GS}	± 16	
Continuous Drain Current (T _J = 150 °C)	T _C = 25 °C	I _D	20 ^c	A
	T _C = 100 °C		20 ^c	
	T _A = 25 °C		15.9 ^b	
	T _A = 100 °C		11 ^b	
Pulsed Drain Current		I _{DM}	60	
Continuous Source-Drain Diode Current	T _C = 25 °C	I _S	20 ^c	
	T _A = 25 °C		2.5 ^b	
Single Pulse Avalanche Current	L = 0.1 mH	I _{AS}	30	
Avalanche Energy		E _{AS}	45	mJ
Maximum Power Dissipation	T _C = 25 °C	P _D	79	W
	T _C = 100 °C		39.5	
	T _A = 25 °C		3.3 ^b	
	T _A = 100 °C		1.6 ^b	
Operating Junction and Storage Temperature Range		T _J , T _{stg}	- 55 to 175	°C

THERMAL RESISTANCE RATINGS					
Parameter		Symbol	Typical	Maximum	Unit
Maximum Junction-to-Ambient ^b	Steady State	R _{thJA}	37	4.5	°C/W
Maximum Junction-to-Case	Steady State	R _{thJC}	1.5	1.9	

Notes:

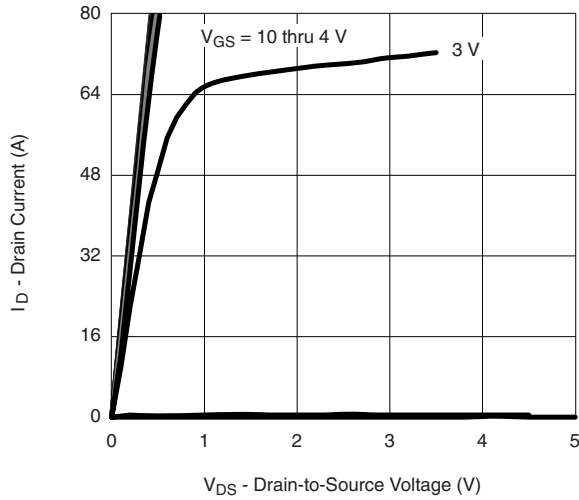
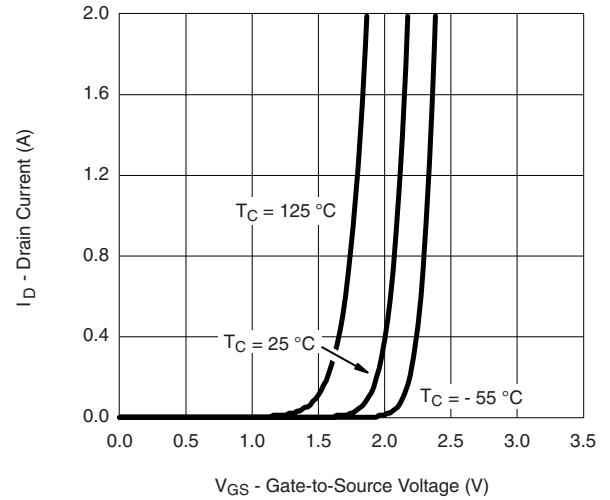
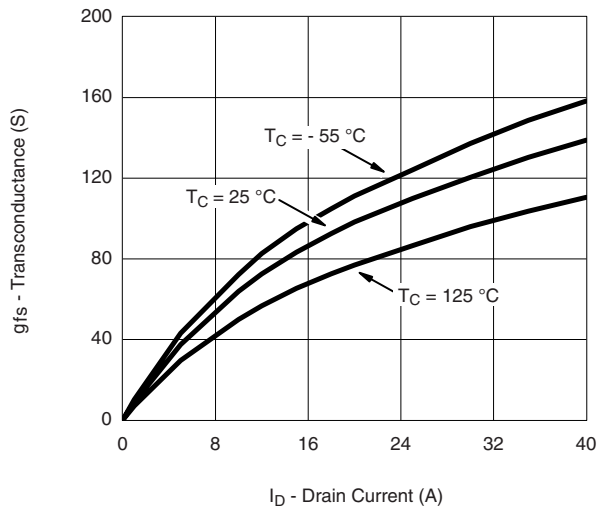
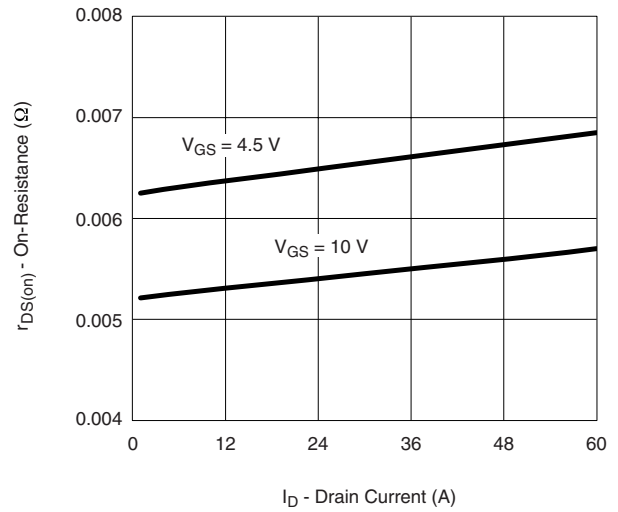
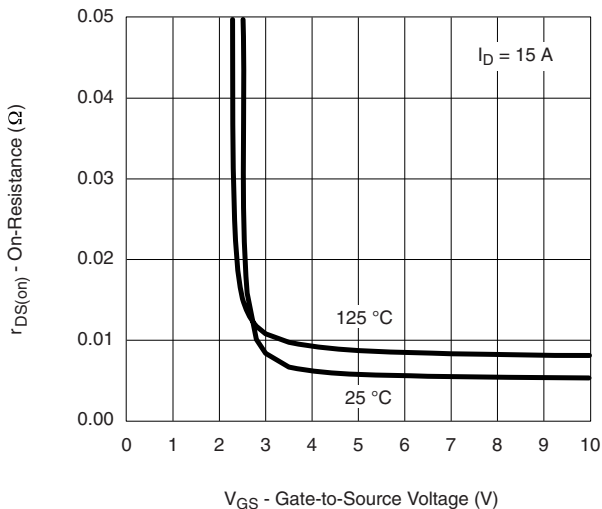
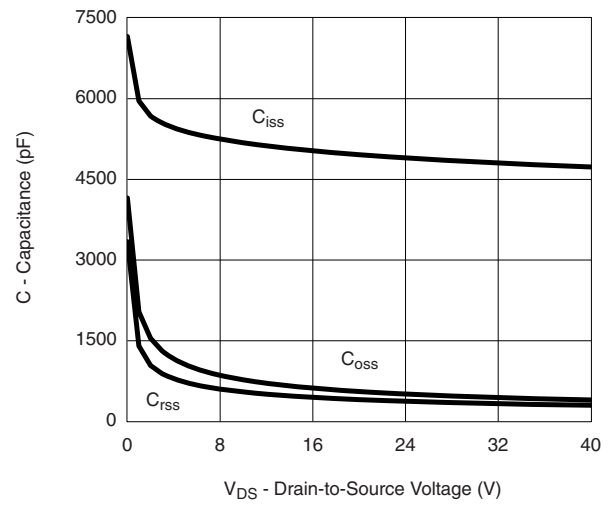
- Based on T_C = 25 °C.
- Surface Mounted on 1" x 1" FR4 board.
- Package limited.

SPECIFICATIONS $T_J = 25\text{ }^\circ\text{C}$, unless otherwise noted						
Parameter	Symbol	Test Conditions	Min	Typ	Max	Unit
Static						
Drain-Source Breakdown Voltage	V_{DS}	$V_{GS} = 0\text{ V}, I_D = 250\text{ }\mu\text{A}$	40			V
V_{DS} Temperature Coefficient	$\Delta V_{DS}/T_J$	$I_D = 250\text{ }\mu\text{A}$		35		mV/ $^\circ\text{C}$
$V_{GS(th)}$ Temperature Coefficient	$\Delta V_{GS(th)}/T_J$			- 6.0		
Gate-Source Threshold Voltage	$V_{GS(th)}$	$V_{DS} = V_{GS}, I_D = 250\text{ }\mu\text{A}$	0.8		2.2	V
Gate-Source Leakage	I_{GSS}	$V_{DS} = 0\text{ V}, V_{GS} = \pm 16\text{ V}$			± 100	nA
Zero Gate Voltage Drain Current	I_{DSS}	$V_{DS} = 40\text{ V}, V_{GS} = 0\text{ V}$			1	μA
		$V_{DS} = 40\text{ V}, V_{GS} = 0\text{ V}, T_J = 100\text{ }^\circ\text{C}$			20	
On-State Drain Current ^a	$I_{D(on)}$	$V_{DS} \geq 5\text{ V}, V_{GS} = 10\text{ V}$	30			A
Drain-Source On-State Resistance ^a	$r_{DS(on)}$	$V_{GS} = 10\text{ V}, I_D = 15\text{ A}$		0.0053	0.0065	Ω
		$V_{GS} = 4.5\text{ V}, I_D = 10\text{ A}$		0.0063	0.008	
Forward Transconductance ^a	g_{fs}	$V_{DS} = 15\text{ V}, I_D = 15\text{ A}$		83		S
Dynamic^b						
Input Capacitance	C_{iss}	$V_{DS} = 20\text{ V}, V_{GS} = 0\text{ V}, f = 1\text{ MHz}$		5080		pF
Output Capacitance	C_{oss}			555		
Reverse Transfer Capacitance	C_{rss}			402		
Total Gate Charge	Q_g	$V_{DS} = 20\text{ V}, V_{GS} = 10\text{ V}, I_D = 30\text{ A}$		110	165	nC
				53.6	80	
Gate-Source Charge	Q_{gs}	$V_{DS} = 20\text{ V}, V_{GS} = 4.5\text{ V}, I_D = 30\text{ A}$		8.8		nC
Gate-Drain Charge	Q_{gd}			18.4		
Gate Resistance	R_g		$f = 1\text{ MHz}$		1.2	
Turn-On Delay Time	$t_{d(on)}$	$V_{DD} = 20\text{ V}, R_L = 0.66\text{ }\Omega$ $I_D \cong 30\text{ A}, V_{GEN} = 4.5\text{ V}, R_g = 1\text{ }\Omega$		24	36	ns
Rise Time	t_r			142	215	
Turn-Off Delay Time	$t_{d(off)}$			142	215	
Fall Time	t_f			92	140	
Turn-On Delay Time	$t_{d(on)}$	$V_{DD} = 20\text{ V}, R_L = 0.66\text{ }\Omega$ $I_D \cong 30\text{ A}, V_{GEN} = 10\text{ V}, R_g = 1\text{ }\Omega$		8	16	
Rise Time	t_r			19	30	
Turn-Off Delay Time	$t_{d(off)}$			50	75	
Fall Time	t_f			11	18	
Drain-Source Body Diode Characteristics						
Continuous Source-Drain Diode Current	I_S	$T_C = 25\text{ }^\circ\text{C}$			20	A
Pulse Diode Forward Current ^a	I_{SM}				50	
Body Diode Voltage	V_{SD}	$I_S = 10\text{ A}$		0.76	1.2	V
Body Diode Reverse Recovery Time	t_{rr}	$I_F = 20\text{ A}, di/dt = 100\text{ A}/\mu\text{s}, T_J = 25\text{ }^\circ\text{C}$		36	55	ns
Body Diode Reverse Recovery Charge	Q_{rr}			40	60	nC
Reverse Recovery Fall Time	t_a			20		ns
Reverse Recovery Rise Time	t_b			16		

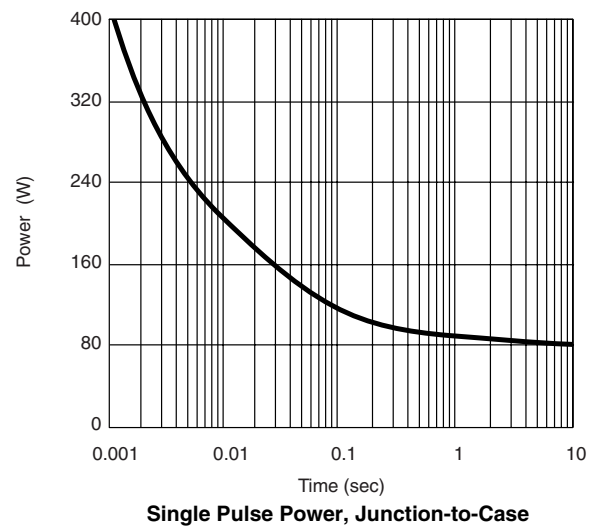
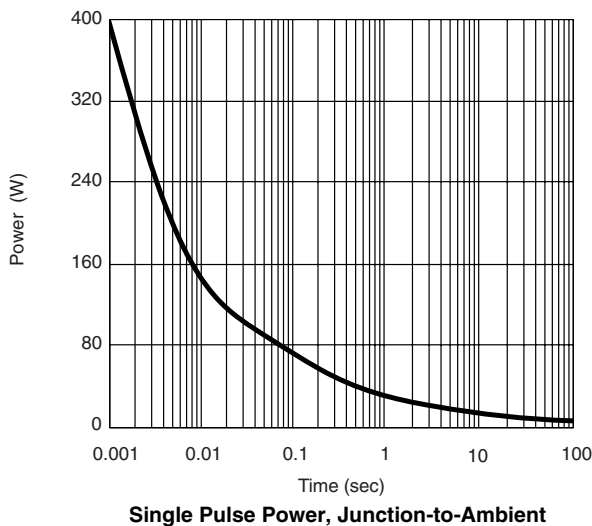
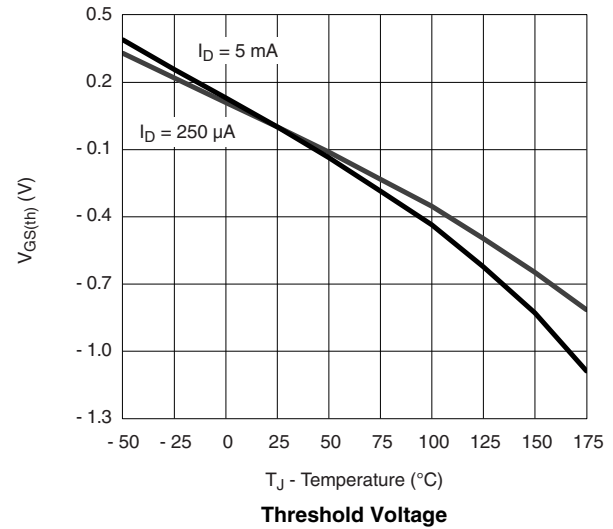
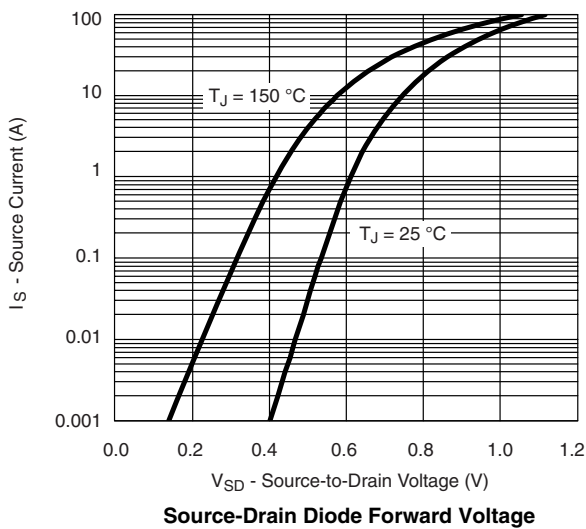
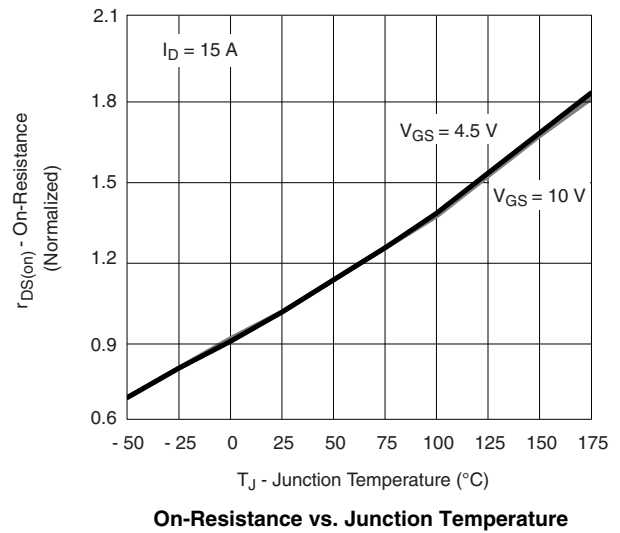
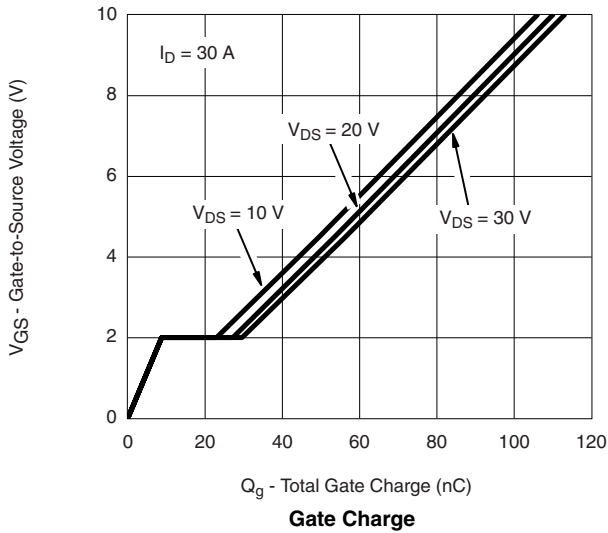
Notes:

- a. Pulse test; pulse width $\leq 300\text{ }\mu\text{s}$, duty cycle $\leq 2\%$.
b. Guaranteed by design, not subject to production testing.

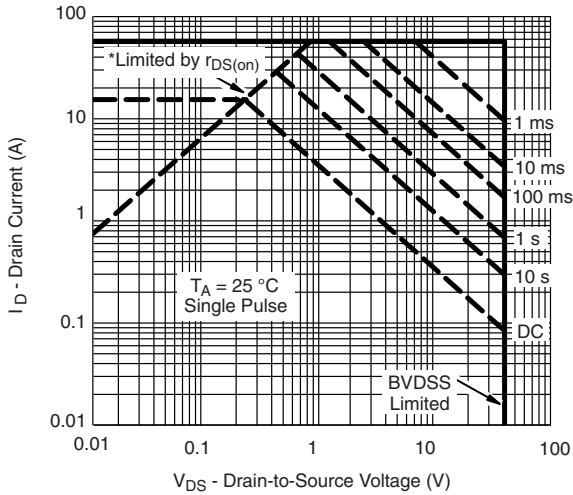
Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted

Output Characteristics

Transfer Characteristics

Transconductance

On-Resistance vs. Drain Current

On-Resistance vs. Gate-to-Source Voltage

Capacitance

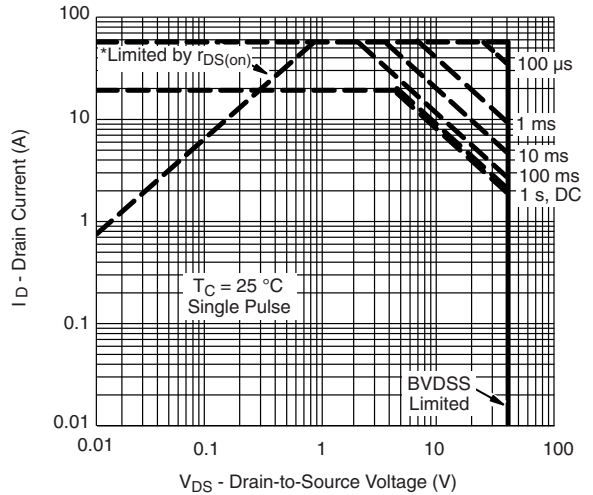
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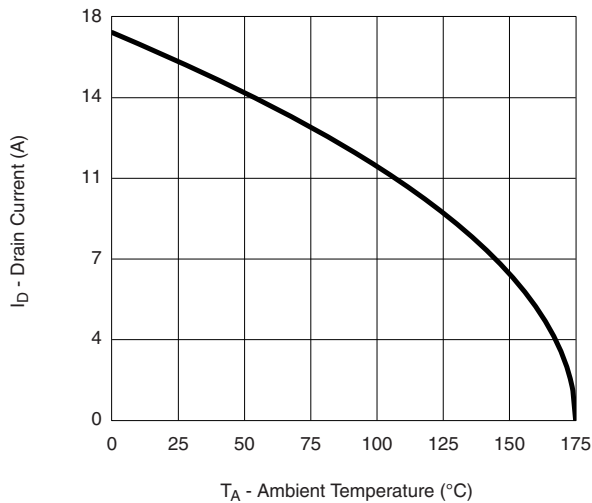
TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted



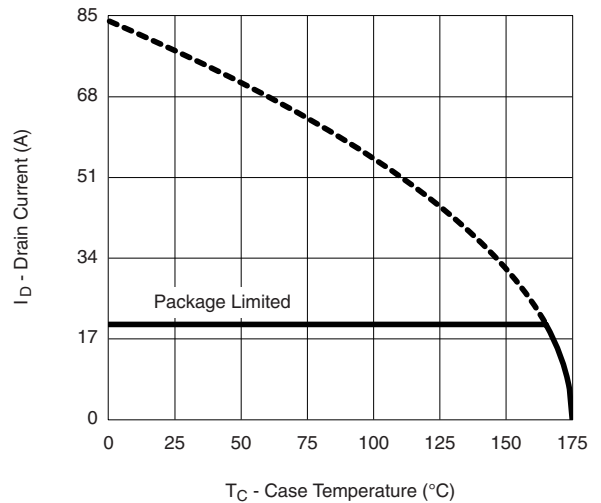
V_{DS} - Drain-to-Source Voltage (V)
 *V_{GS} > minimum V_{GS} at which r_{DS(on)} is specified
Safe Operating Area, Junction-to-Ambient



V_{DS} - Drain-to-Source Voltage (V)
 *V_{GS} > minimum V_{GS} at which r_{DS(on)} is specified
Safe Operating Area, Junction-to-Case

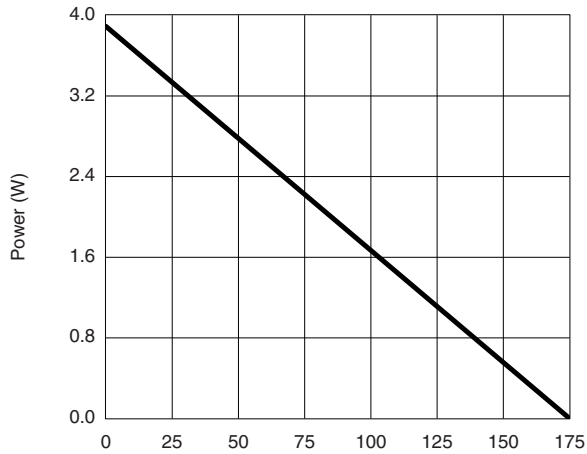


T_A - Ambient Temperature (°C)
Current Derating*, Junction-to-Ambient

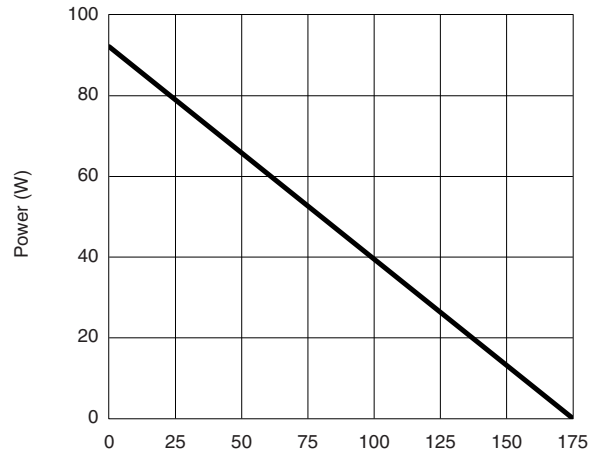


T_C - Case Temperature (°C)
Current Derating*, Junction-to-Case

TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted



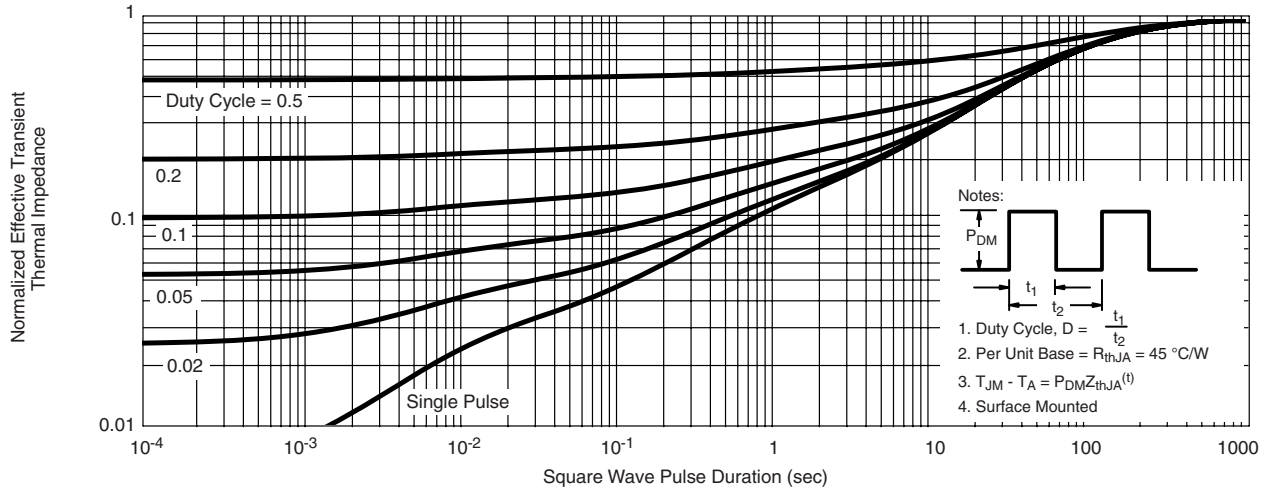
T_A - Ambient Temperature (°C)
Power Derating*, Junction-to-Ambient



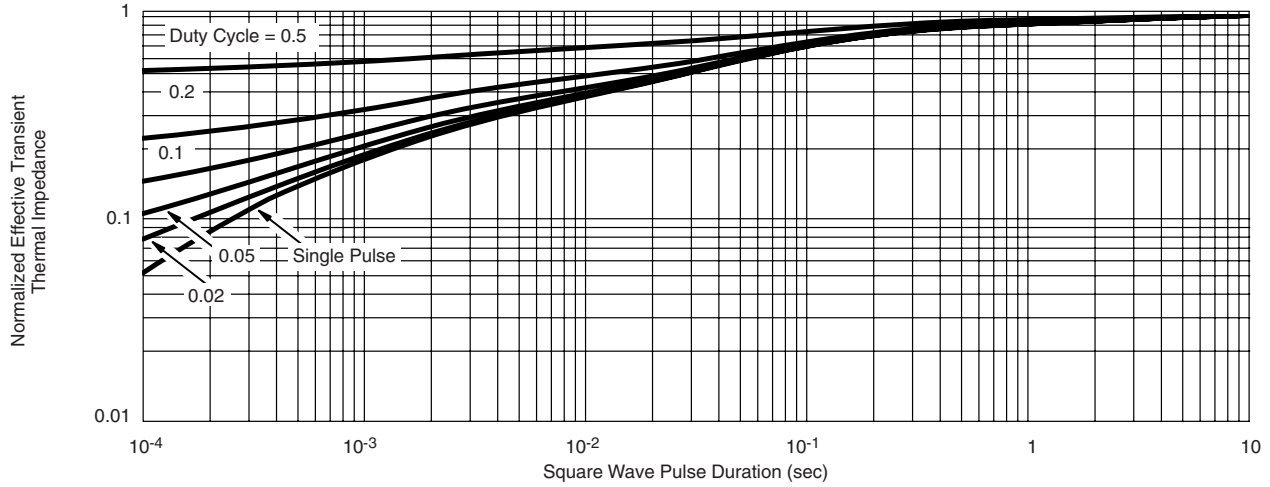
T_C - Case Temperature (°C)
Power Derating*, Junction-to-Case

*The power dissipation P_D is based on T_{J(max)} = 175 °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.

TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted



Normalized Thermal Transient Impedance, Junction-to-Ambient



Normalized Thermal Transient Impedance, Junction-to-Case

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